Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/511,597	LOUIS ET AL.	
Examiner	Art Unit	

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Tam M. Nguyen

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Class	Subclass	Date	Examiner		
208	213 240 221 231 254R 196 201	12/5/2007	tn		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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east	12/5/2007 12/10/07	TN
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